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BSI Standards Publication

Space systems — Evaluation of radiation effects on Commercial-Off-The-Shelf (COTS) parts for use on low-orbit satellite

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National foreword

This British Standard is the UK implementation of ISO 21980:2020.

The UK participation in its preparation was entrusted to Technical Committee ACE/68, Space systems and operations.

A list of organizations represented on this committee can be obtained on request to its secretary.

This publication does not purport to include all the necessary provisions of a contract. Users are responsible for its correct application.

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Space systems — Evaluation of radiation effects on Commercial-Off-The-Shelf (COTS) parts for use on low-orbit satellite

Systèmes spatiaux — Évaluation des effets des radiations sur les parties commerciales sur étagère (COTS) destinées aux satellites à orbite basse



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Contents

Page

Foreword	iv
Introduction	v
1 Scope	1
2 Normative references	1
3 Terms and definitions	1
4 Abbreviated terms	3
5 Radiation resistance design	4
5.1 Overview.....	4
5.2 Basic idea of using COTS parts.....	5
5.2.1 Concept of parts selection.....	5
5.2.2 COTS parts evaluation.....	5
5.2.3 Concept of evaluation method.....	5
5.2.4 Concept of application of COTS parts/consumer technology.....	5
5.3 Space radiation environment prediction.....	5
5.3.1 Space environment.....	5
5.3.2 Space radiation environment model.....	6
5.3.3 Various parameters.....	6
5.3.4 Environmental conditions necessary for evaluation.....	6
6 Radiation tolerance test	7
6.1 Types of irradiation test.....	7
6.1.1 Cobalt 60 (gamma ray) irradiation test.....	7
6.1.2 Proton beam irradiation test.....	7
6.1.3 Heavy ion test.....	7
6.2 Alternative irradiation test — Laser pulse test.....	7
6.3 Test procedure.....	7
6.3.1 Total dose test.....	7
6.3.2 Single event test.....	7
6.3.3 Displacement damage test.....	7
6.3.4 Laser pulse test for SEE test.....	7
Annex A (informative) Radiation resistance design procedure	8
Annex B (informative) Total dose prediction method	13
Annex C (informative) Radiation guidelines for total dose using contour maps	19
Annex D (informative) Comparative example between model prediction and measured values	23
Annex E (informative) Radiation deterioration of electronic components	25
Annex F (informative) Overview of single event effect	27
Annex G (informative) Measures for single events of electronic components	29
Annex H (informative) Measures for single events of devices	31
Annex I (informative) Prediction method of displacement damage	33
Annex J (informative) Resistance for displacement damage of each device	35
Annex K (informative) Displacement damage test guideline for semiconductor device	38
Annex L (informative) Laser pulse test method	44
Bibliography	46

This is a preview of "BS ISO 21980:2020". [Click here to purchase the full version from the ANSI store.](#)

Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

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For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT), see www.iso.org/iso/foreword.html.

This document was prepared by Technical Committee ISO/TC 20, *Aircraft and space vehicles*, Subcommittee SC 14, *Space systems and operations*.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

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Introduction

This document describes methods of evaluating the radiation effects on COTS (Commercial-Off-The-Shelf) parts used in low Earth orbit (LEO) satellites. Many small (<180 kg) and nano/microsatellites (1 kg to 50 kg) are launched to LEO altitudes where space radiation exists but is less than at higher altitudes. As a result, the designers and manufacturers of such satellites are using COTS semiconductor devices for their satellite components and boards. New industries taking advantage of nano/microsatellite and CubeSat [1,33 kg × (1U-3U)] satellite capabilities now include IT ventures, mobile phones, and internet industries along with universities and research institutions.

Satellite manufacturers who prioritize investment efficiency also aim to extend mission lifetimes (up to three, five and ten years) longer than one-year missions that were common for educational and technical demonstrations using nano/microsatellites.

Even with relatively lower space radiation conditions in LEO compared to higher orbits, a longer mission life in LEO poses critical radiation environment constraints for COTS devices onboard small and nano/microsatellites as well as CubeSats.

While there are methods of evaluating the radiation resistance of space parts, there are limited methods for evaluating COTS parts used for LEO satellites and these are often based on legacy parts usage.

This document provides guidance for evaluating radiation tolerance of COTS parts that can help increase confidence levels of longer-term mission lifetimes.

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Space systems — Evaluation of radiation effects on Commercial-Off-The-Shelf (COTS) parts for use on low-orbit satellite

1 Scope

This document outlines the evaluation methods for environmental tests that can be conducted on COTS (Commercial-Off-The-Shelf) spacecraft parts intended for use on LEO satellites. The radiation effects considered consist of total dosage, single event, and displacement damage. In addition, this document describes tests that are useful for satellites operating in LEO.

2 Normative references

There are no normative references in this document.

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- ISO Online browsing platform: available at <https://www.iso.org/obp>
- IEC Electropedia: available at <http://www.electropedia.org/>

3.1

galactic cosmic rays

GCR

high-energy-charged particle *fluxes* (3.2) penetrating the heliosphere from local interstellar space

Note 1 to entry: Galactic cosmic rays are composed primarily of high-energy protons and atomic nuclei. Upon impact with the Earth's atmosphere, cosmic rays can produce showers of secondary particles that sometimes reach the Earth's surface. There is evidence that a significant fraction of primary cosmic rays originate from stellar supernova explosions and perhaps from active galactic nuclei.

[SOURCE: ISO 15390:2004, 2.1, modified — Note 1 to entry has been added.]

3.2

flux

number of particles passing through a specific unit area per unit time

[SOURCE: ISO 12208:2015, 2.3]

3.3

fluence

time-integrated *flux* (3.2)

Note 1 to entry: Fluence is measured as the flux per unit area per unit time. This is used to express the environment during the operational lifetime of a spacecraft or space instrument. The integrated particles fluence unit is expressed as particles m^{-2} . The energy integral fluence unit is expressed as particles $\text{m}^{-2} \text{MeV}^{-1}$. When the directional fluence is included, add per steradian (sr^{-1}).

[SOURCE: ISO 12208:2015, 2.4, modified — Note 1 to entry has been added.]